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09/192,583	МОТОУАМА, Т	ETSURO
Examiner	Art Unit	
CHUONG T. HO	2619	

SEARCHED					
Class	Subclass	Date	Examiner		
709	206	5/9/2008	СН		
709	224	5/9/2008	СН		
710	15	5/9/2008	СН		
709	203,202	5/9/2008	СН		
709	202-205	5/9/2008	СН		
709	223	5/9/2008	СН		
709	217	5/9/2008	СН		
379	88.22	5/9/2008	СН		
370	395, 409	5/9/2008	СН		
370	252, 384	5/9/2008	СН		
370	401,353	5/9/2008	СН		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
709	206, 224	5/9/2008	СН	
370	401, 352	5/9/2008	СН	
370	353	5/9/2008	CH	
Text search of USPGPUB (see inter search history)		5/9/2008	СН	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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Cosulting with Luu Le (Priamry Examiner AU 2141 (2-3884)	5/10/2008	СН		
Interviewed conference with Primary Examiner Philip Tran AU 2155 (2- 3991)	5/10/2008	СН		
Consulting with Dinh Dung (QPQA) (Office of Patent Quality Assurance) (2-3943)	5/9/2008	СН		
Cosnsulting with Orgad Edan (SPE AU 2619)	5/9/2005	СН		

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